

Search Notes

Application/Control No.

10/625,664

Examiner

Thien M. Le

Applicant(s)/Patent under
Reexamination

HABA, YOSHITO

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	462.01- 462.47	1/5/2005	LTM
	472.01		
	472.02		
	472.03		
	454		
	455		
	470		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/4/2005	LTM